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C.   Amendments to the Claims.

1. (Currently Amended) A programmable logic device assembly, comprising:

a programmable logic circuit that provides functions according to configuration data including a self-test function; and

at least one nonvolatile store **of the programmable logic device assembly** coupled to the programmable logic circuit that provides self-test configuration data for the programmable logic circuit and can subsequently store user configuration data.

2. (Currently Amended) The programmable logic device assembly of claim 1, wherein:

the programmable **logic** circuit can provide a self-test result when configured for self-test function.

3. (Original) The programmable logic device assembly of claim 2, further including:

a test port for providing the self-test result in a predetermined format.

4. (Original) The programmable logic device assembly of claim 1, wherein:

the at least one nonvolatile store includes a first nonvolatile store formed with the programmable logic circuit on a single integrated circuit die.

5. (Original) The programmable logic device assembly of claim 4, wherein:

the first nonvolatile store includes re-programmable nonvolatile circuit elements.

6. (Original) The programmable logic device assembly of claim 5, wherein:

the first nonvolatile store includes electrically erasable programmable read-only-memory cells.

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7. **(Currently Amended)** The programmable logic device assembly of claim 4, wherein:

    the self-test configuration data in the at least one nonvolatile store is set by at least one manufacturing process step **for the programmable logic device assembly.**

8. **(Currently Amended)** The programmable logic device assembly of claim 7, wherein:

    the at least one nonvolatile store includes a mask programmable read-only-memory that ~~stored~~ **stores** self-test configuration data and a separate nonvolatile memory that can store user configuration data.

9. (Original) The programmable logic device assembly of claim 1, wherein:

    the at least one nonvolatile store includes at least two sectors and self-test configuration data is stored in a first sector.

10. (Original) The programmable logic device assembly of claim 9, wherein:

    the first sector is a boot sector.

11. **(Currently Amended)** A method, comprising the steps of:

    performing a self-test on a programmable logic circuit **of one package** according to self-test configuration data in a self-test nonvolatile store **of the one package;** and

    storing user configuration data in a user nonvolatile store if the programmable logic circuit passes the self-test.

12. (Original) The method of claim 11, wherein:

    the self-test nonvolatile store is the same as the user nonvolatile store.

13. (Original) The method of claim 12, wherein:

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storing user configuration data includes programming user configuration data in locations that stored self-test configuration data.

14. (Currently Amended) The method of claim 12, wherein:

storing user configuration data includes ~~programming~~ storing user configuration data in locations that are different than those that store self-test configuration data.

15. (Currently Amended) The method of claim 11, further including:

forming the self-test nonvolatile store on the same die as the programmable logic circuit.

16. (Currently Amended) The method of claim 11, further including:

assembling the programmable logic circuit on one die with the nonvolatile store on another die into the one package.

17. (Original) The programmable logic circuit of claim 16, wherein:

the one package is a multi-chip module.

18. (Currently Amended) A programmable logic assembly self-test method, comprising the steps of:

storing self-test information in a first nonvolatile store of the assembly that places a programmable logic circuit of the assembly into a self-test configuration;

executing a self-test on the programmable logic circuit; and

providing user configuration information that places the programmable logic circuit in a user configuration.

19. (Original) The method of claim 18, wherein:

the user configuration data is stored in the first nonvolatile store.

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20. (Original) The method of claim 18, wherein:

the user configuration data is stored in a second nonvolatile store that is different than the first nonvolatile store.

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